

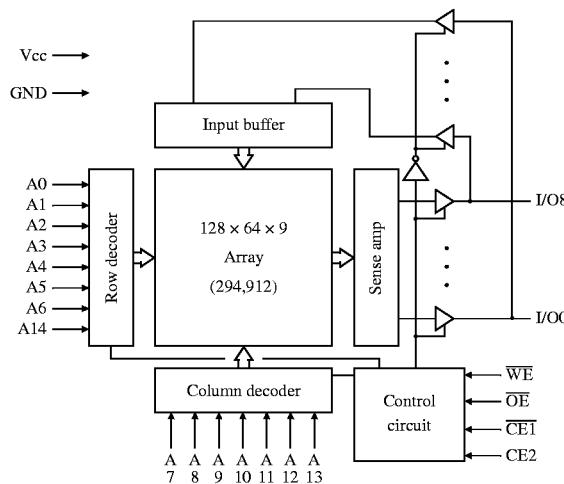
AS7C259

SRAM

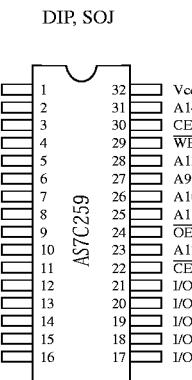
Features

- Organization: 32,768 words × 9 bits
- High speed
 - 15/20/25 ns address access time
 - 4/5/6 ns output enable access time
- Low power consumption
 - Active: 633 mW max (10 ns cycle)
 - Standby: 11 mW max, CMOS I/O
 - Very low DC component in active power
- 2.0V data retention
- Equal access and cycle times
- Easy memory expansion with $\overline{CE1}$, $\overline{CE2}$, and \overline{OE} inputs
- TTL-compatible, three-state I/O
- 32-pin JEDEC standard packages
 - 300 mil PDIP and SOJ
- ESD protection ≥ 2000 volts
- Latch-up current ≥ 200 mA

Logic block diagram



Pin arrangement



Selection guide

	7C259-15	7C259-20	7C259-25	Unit
Maximum address access time	15	20	25	ns
Maximum output enable access time	4	5	6	ns
Maximum operating current	110	100	90	mA
Maximum CMOS standby current	2.0	2.0	2.0	mA



Functional description

The AS7C259 is a high performance CMOS 294,912-bit Static Random Access Memory (SRAM) organized as 32,768 words \times 9 bits. It is designed for memory applications where fast data access, low power, and simple interfacing are desired.

SRAM

Equal address access and cycle times (t_{AA} , t_{RC} , t_{WC}) of 15/20/25 ns with output enable access times (t_{OE}) of 4/5/6 ns are ideal for high performance applications. Active high and low chip enables (CET , $CE2$) permit easy memory expansion with multiple-bank memory systems.

When CET is High or $CE2$ is Low the device enters standby mode. The standard AS7C259 is guaranteed not to exceed 11 mW power consumption in standby mode.

A write cycle is accomplished by asserting write enable (WE) and both chip enables (CET , $CE2$). Data on the input pins I/O0-I/O7 is written on the rising edge of WE (write cycle 1) or the active-to-inactive edge of CET or $CE2$ (write cycle 2). To avoid bus contention, external devices should drive I/O pins only after outputs have been disabled with output enable (OE) or write enable (WE).

A read cycle is accomplished by asserting output enable (OE) and both chip enables (CET , $CE2$), with write enable (WE) High. The chip drives I/O pins with the data word referenced by the input address. When either chip enable or output enable is inactive, or write enable is active, output drivers stay in high-impedance mode.

All chip inputs and outputs are TTL-compatible, and operation is from a single 5V supply. The AS7C259 is packaged in common industry standard packages.

Absolute maximum ratings

Parameter	Symbol	Min	Max	Unit
Voltage on any pin relative to GND	V_t	-0.5	+7.0	V
Power dissipation	P_D	-	1.0	W
Storage temperature (plastic)	T_{stg}	-55	+150	°C
Temperature under bias	T_{bias}	-10	+85	°C
DC output current	I_{out}	-	20	mA

Stresses greater than those listed under **Absolute Maximum Ratings** may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Truth table

CET	$CE2$	WE	OE	Data	Mode
H	X	X	X	High Z	Standby (I_{SB} , I_{SB1})
X	L	X	X	High Z	Standby (I_{SB} , I_{SB1})
L	H	H	H	High Z	Output disable
L	H	H	L	D_{out}	Read
L	H	L	X	D_{in}	Write

Key: X = Don't Care, L = Low, H = High

Recommended operating conditions

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	4.5	5.0	5.5	V
	GND	0.0	0.0	0.0	V
Input voltage	V_{IH}	2.2	-	$V_{CC}+1.0$	V
	V_{IL}	-0.5 [†]	-	0.8	V

[†] V_{IL} min = -3.0V for pulse width less than $t_{RC}/2$.

DC operating characteristics¹(V_{CC} = 5V ± 10%, GND = 0V, T_a = 0°C to +70°C)

Parameter	Symbol	Test conditions	Min	Max	Min	Max	Min	Max	Unit
Input leakage current	I _{LI}	V _{CC} = Max, V _{in} = GND to V _{CC}	–	1	–	1	–	1	µA
Output leakage current	I _{LO}	CET = V _{IH} or CE2 = V _{IL} , V _{CC} = Max, V _{out} = GND to V _{CC}	–	1	–	1	–	1	µA
Operating power supply current	I _{CC}	CET = V _{IL} , CE2 = V _{IH} , f = f _{max} , I _{out} = 0 mA	–	110	–	100	–	90	mA
Standby power supply current	I _{SB}	CET = V _{IH} or CE2 = V _{IL} , f = f _{max}	–	30	–	30	–	25	mA
	I _{SB1}	CET ≥ V _{CC} – 0.2V or CE2 ≤ 0.2V, V _{in} ≤ 0.2V or V _{in} ≥ V _{CC} – 0.2V, f = 0	–	2.0	–	2.0	–	2.0	mA
Output voltage	V _{OL}	I _{OL} = 8 mA, V _{CC} = Min	–	0.4	–	0.4	–	0.4	V
	V _{OH}	I _{OH} = –4 mA, V _{CC} = Min	2.4	–	2.4	–	2.4	–	V

Capacitance²(f = 1 MHz, T_a = room temperature, V_{CC} = 5V)

Parameter	Symbol	Signals	Test conditions	Max	Unit
Input capacitance	C _{IN}	A, CET, CE2, WE, OE	V _{in} = 0V	5	pF
I/O capacitance	C _{I/O}	I/O	V _{in} = V _{out} = 0V	7	pF

Read cycle^{3,9,12}(V_{CC} = 5V ± 10%, GND = 0V, T_a = 0°C to +70°C)

Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	15	–	20	–	25	–	ns	
Address access time	t _{AA}	–	15	–	20	–	25	ns	3
Chip enable (CET) access time	t _{ACE1}	–	15	–	20	–	25	ns	3, 12
Chip enable (CE2) access time	t _{ACE2}	–	15	–	20	–	25	ns	3, 12
Output enable (OE) access time	t _{OE}	–	4	–	5	–	6	ns	
Output Hold from address change	t _{OH}	3	–	3	–	3	–	ns	5
CET Low to Output in Low Z	t _{CLZ1}	3	–	3	–	3	–	ns	4, 5, 12
CE2 High to Output in Low Z	t _{CLZ2}	3	–	3	–	3	–	ns	4, 5, 12
CET High to Output in High Z	t _{CHZ1}	–	4	–	5	–	6	ns	4, 5, 12
CE2 Low to Output in High Z	t _{CHZ2}	–	4	–	5	–	6	ns	4, 5, 12
OE Low to Output in Low Z	t _{OLZ}	0	–	0	–	0	–	ns	4, 5
OE High to Output in High Z	t _{OHZ}	–	4	–	5	–	6	ns	4, 5
Power up time	t _{PU}	0	–	0	–	0	–	ns	4, 5, 12
Power down time	t _{PD}	–	15	–	20	–	25	ns	4, 5, 12

Key to switching waveforms

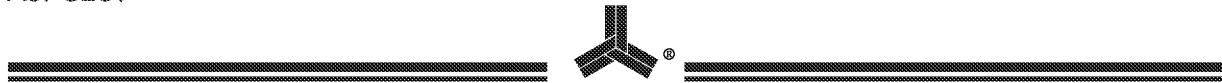
Rising input

Falling input

Undefined output/don't care

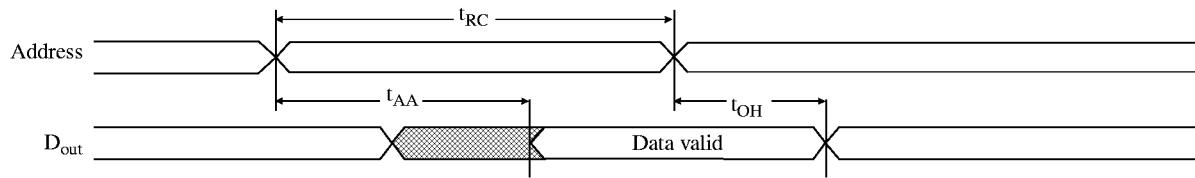
SRAM

AS7C259



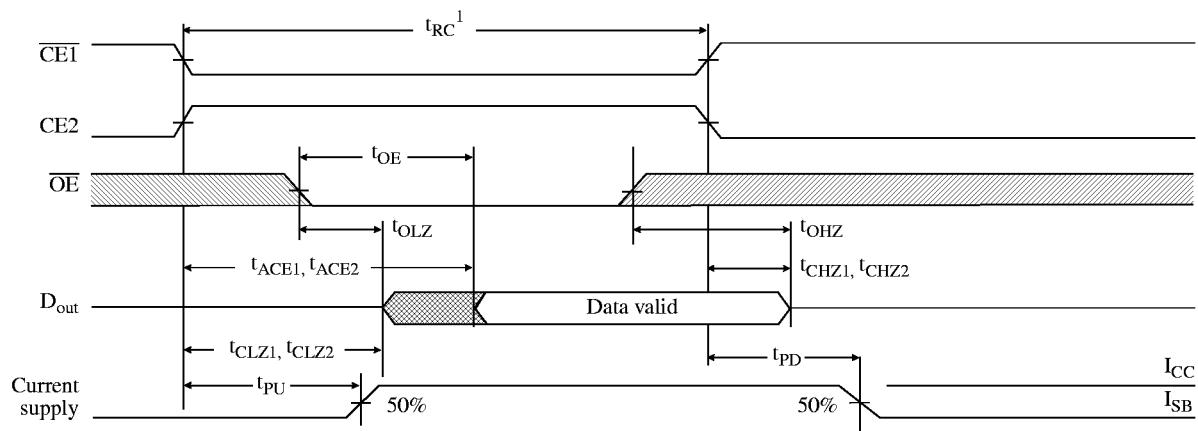
Read waveform 1 ^{3,6,7,9,I2}

Address controlled



Read waveform 2 ^{3,6,8,9,I2}

$\overline{CE1}$ and $CE2$ controlled

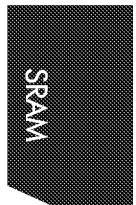
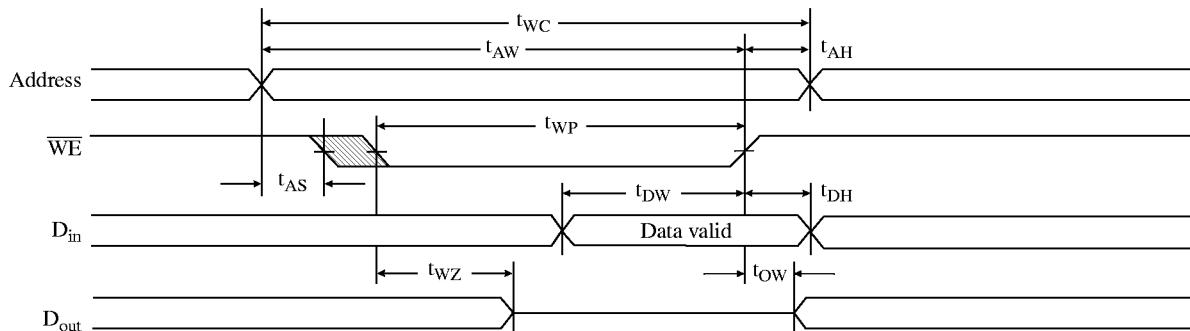
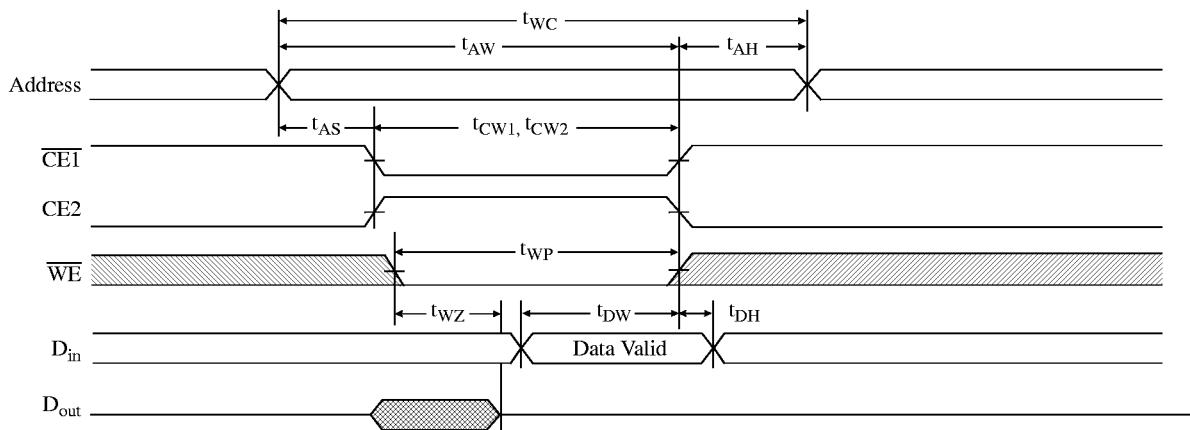


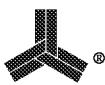
Write cycle ^{II,I2}

($V_{CC} = 5V \pm 10\%$, $GND = 0V$, $T_a = 0^\circ C$ to $+70^\circ C$)

-15 -20 -25

Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Write cycle time	t_{WC}	15	–	20	–	20	–	ns	
Chip enable ($CE1$) to write end	t_{CW1}	12	–	12	–	15	–	ns	12
Chip enable ($CE2$) to write end	t_{CW2}	12	–	12	–	15	–	ns	12
Address setup to write end	t_{AW}	12	–	12	–	15	–	ns	
Address setup time	t_{AS}	0	–	0	–	0	–	ns	12
Write pulse width	t_{WP}	9	–	12	–	15	–	ns	
Address hold from end of write	t_{AH}	0	–	0	–	0	–	ns	
Data valid to write end	t_{DW}	8	–	10	–	10	–	ns	
Data hold time	t_{DH}	0	–	0	–	0	–	ns	4, 5
Write enable to output in High Z	t_{WZ}	–	5	–	5	–	5	ns	4, 5
Output active from write end	t_{OW}	3	–	3	–	3	–	ns	4, 5

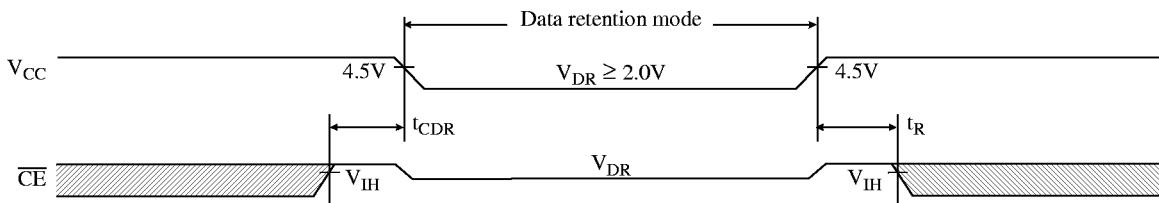
Write waveform 1 *I0,I1,I2* \overline{WE} controlledWrite waveform 2 *I0,I1,I2* $\overline{CE1}$ and $CE2$ controlled



Data retention characteristics

Parameter	Symbol	Test conditions	Min	Max	Unit
V_{CC} for data retention	V_{DR}	$V_{CC} = 2.0V$	2.0	–	V
Data retention current	I_{CCDR}	$\overline{CE} \geq V_{CC} - 0.2V$ or $CE2 \leq 0.2V$	–	150	μA
Chip deselect to data retention time	t_{CDR}		0	–	ns
Operation recovery time	t_R	$V_{in} \geq V_{CC} - 0.2V$ or $V_{in} \leq 0.2V$	t_{RC}	–	ns
Input leakage current	$ I_{II} $		–	1	μA

Data retention waveform



AC test conditions

- Output load: see Figure B,
except for t_{CLZ} and t_{CHZ} see Figure C.
- Input pulse level: GND to 3.0V. See Figure A.
- Input rise and fall times: 5 ns. See Figure A.
- Input and output timing reference levels: 1.5V.

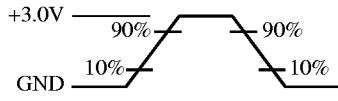


Figure A: Input waveform

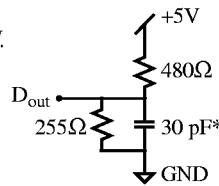
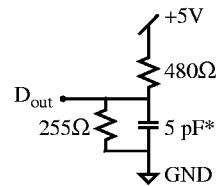


Figure B: Output load

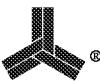
Thevenin Equivalent:
 $D_{out} \xrightarrow{168\Omega} +1.728V$

Figure C: Output load for t_{CLZ}, t_{CHZ}

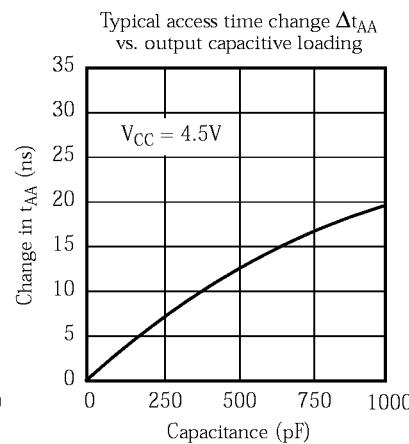
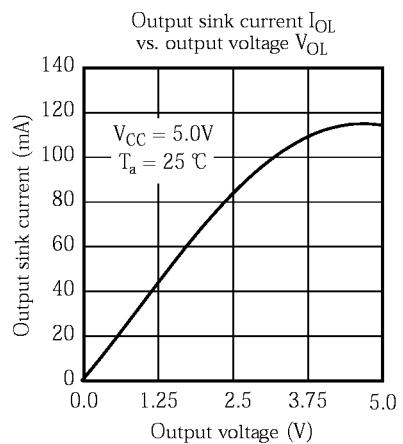
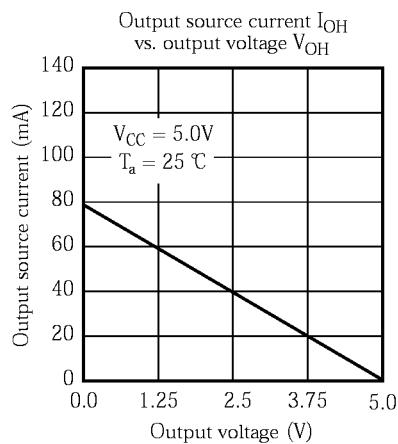
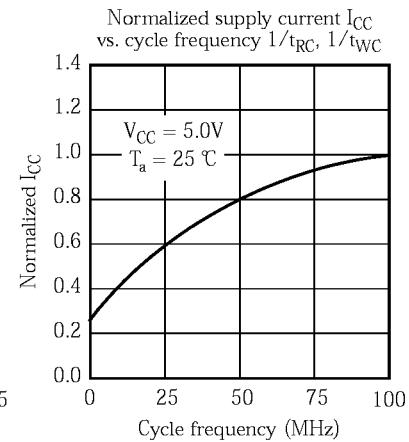
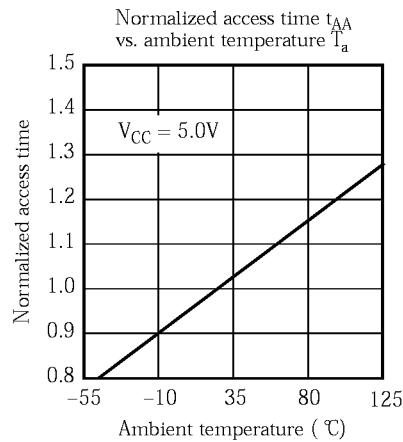
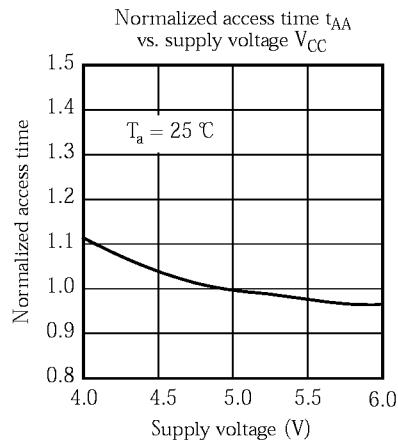
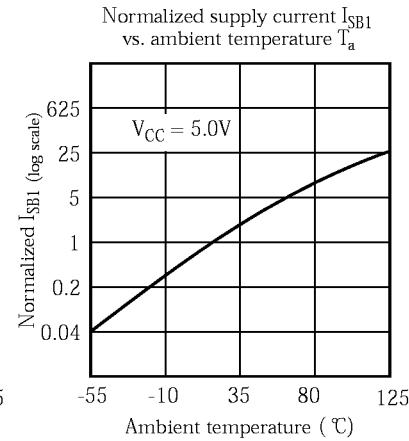
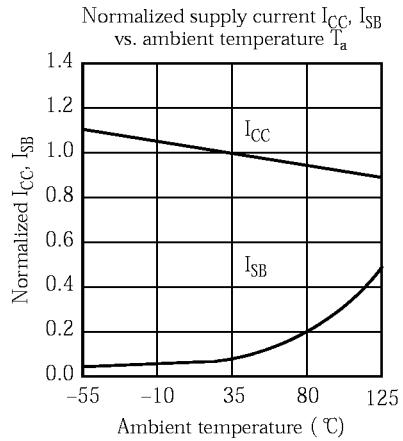
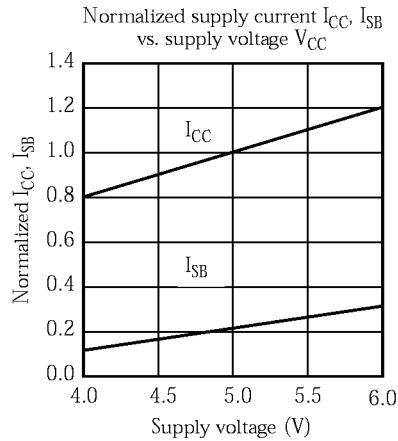
*including scope
and jig capacitance

Notes

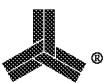
- 1 During V_{CC} power-up, a pull-up resistor to V_{CC} on \overline{CE} is required to meet I_{SB} specification.
- 2 This parameter is sampled and not 100% tested.
- 3 For test conditions, see AC Test Conditions, Figures A, B, C.
- 4 t_{CLZ} and t_{CHZ} are specified with $CL = 5pF$ as in Figure C. Transition is measured $\pm 500mV$ from steady-state voltage.
- 5 This parameter is guaranteed but not tested.
- 6 WE is High for read cycle.
- 7 \overline{CE} and OE are Low and $CE2$ is High for read cycle.
- 8 Address valid prior to or coincident with \overline{CE} transition Low.
- 9 All read cycle timings are referenced from the last valid address to the first transitioning address.
- 10 \overline{CE} or WE must be High or $CE2$ Low during address transitions.
- 11 All write cycle timings are referenced from the last valid address to the first transitioning address.
- 12 \overline{CE} and $CE2$ have identical timing



Typical AC and DC characteristics



AS7C259



AS7C259 ordering codes

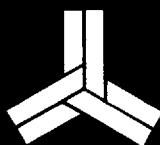
Package / Access Time	15 ns	20 ns	25 ns
Plastic DIP, 300 mil	AS7C259-15PC	AS7C259-20PC	AS7C259-25PC
Plastic SOJ, 300 mil	AS7C259-15JC	AS7C259-20JC	AS7C259-25JC

Shaded areas contain advance information.

SRAM

AS7C259 part numbering system

AS7C	256	-XX	X	C
SRAM prefix	Device number	Access time	Package: P = PDIP 300 mil J = SOJ 300 mil T = TSOP 8x14	Commercial temperature range, 0 °C to 70 °C

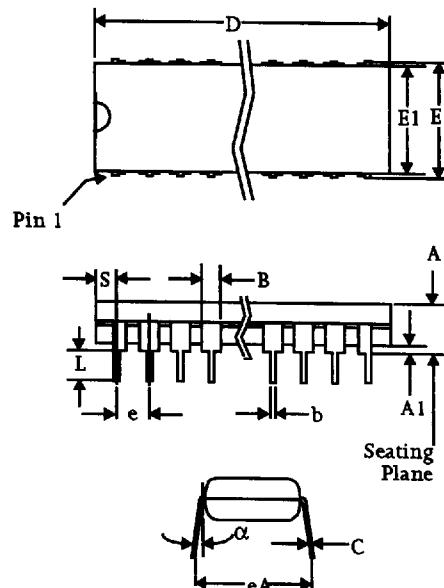


Package diagrams

Plastic dual in-line package (PDIP)

	20-pin 300 mil		28-pin 300 mil		32-pin 300 mil		32-pin 400 mil	
	Min	Max	Min	Max	Min	Max	Min	Max
A	-	0.175	-	0.175	-	0.180	-	0.200
A1	0.010	-	0.010	-	0.015	-	0.015	-
B	0.046	0.054	0.058	0.064	0.045	0.055	0.045	0.065
b	0.018	0.024	0.016	0.022	0.015	0.021	0.014	0.022
C	0.008	0.014	0.008	0.014	0.008	0.012	0.009	0.015
D	-	0.980	-	1.400	-	1.571	-	1.620
E	0.290	0.310	0.295	0.320	0.300	0.325	0.390	0.425
E1	0.263	0.293	0.278	0.298	0.280	0.295	0.340	0.390
e	0.100 BSC		0.100 BSC		0.100 BSC		0.100 BSC	
eA	0.310	0.350	0.330	0.370	0.330	0.370	0.430	0.470
L	0.110	0.130	0.120	0.140	0.110	0.142	0.118	0.162
α	0°	15°	0°	15°	0°	15°	0°	15°
S	-	0.040	-	0.055	-	0.043	-	0.065

Dimensions in inches



Plastic small outline J-bend (SOJ)

	20/26-pin 300 mil		28-pin 300 mil		32-pin 300 mil		28-pin 400 mil		32-pin 400 mil		36-pin 400 mil		40-pin 400 mil		42-pin 400 mil		44-pin 400 mil		
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
A	-	0.140	-	0.140	-	0.145	0.132	0.146	-	0.145	-	-	-	0.145	0.128	0.148	0.128	0.148	
A1	0.020	-	0.025	-	0.025	-	0.062	-	0.025	-	-	-	0.025	-	0.025	-	0.025	-	
A2	0.095	0.105	0.095	0.105	0.086	0.105	0.105	115	0.086	0.115	0.102 NOM	0.086	0.115	1.105	1.115	1.105	1.115		
B	0.025	0.032	0.028 TYP		0.026	0.032	0.024	0.032	0.026	0.032	-	0.032	0.026	0.032	0.026	0.032	0.026	0.032	
b	0.016	0.022	0.018 TYP		0.014	0.020	0.013	0.021	0.015	0.020	0.013	0.021	0.015	0.022	0.015	0.020	0.015	0.020	
c	0.008	0.014	0.010 TYP		0.006	0.013	0.005	0.012	0.007	0.013	-	-	0.007	0.014	0.007	0.013	0.007	0.013	
D	-	0.686	-	0.730	0.820	0.830	0.720	0.729	0.820	0.830	0.920	0.930	1.015	1.035	1.070	1.080	1.120	1.130	
E	0.327	0.347	0.327	0.347	0.330	0.340	0.430	0.440	0.435	0.445	0.350	0.390	0.435	0.445	0.370 NOM	0.370 NOM			
E1	0.295	0.305	0.295	0.305	0.292	0.305	0.395	0.405	0.395	0.405	0.400 NOM	0.395	0.405	0.395	0.405	0.395	0.405		
E2	0.245	0.285	0.245	0.285	0.250	0.275	0.354	0.378	0.360	0.380	0.435	0.445	0.348	0.390	0.435	0.445	0.435	0.445	
e	0.050 BSC		0.050 BSC		0.050 BSC		0.050 BSC		0.050 BSC		0.045	0.055	0.050 BSC		0.050 NOM		0.050 NOM		

Dimensions in inches

